

## PCN# 20210315001.1 Qualification of new Fab site (MIHO8 or FFAB) using qualified Process Technology, Die Revision, Datasheet update and additional Assembly site/BOM options for select devices Change Notification / Sample Request

Date:March 16, 2021To:PREMIER FARNELLPCN

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments (TI). The details of this change are on the following pages, and are in alignment with our standard product change notification (PCN) <u>process</u>.

TI requires acknowledgement of receipt of this notification within 30 days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If samples or additional data are required, requests must be received within 30 days of acknowledgement, given that samples are not built ahead of the change.

The Proposed First Ship date in this PCN letter is the earliest possible date that customers could receive the changed material. It is our commitment that the changed device will not ship before that date. If samples are requested within the 30 day sample request window, customers will still have 30-days to complete their evaluation regardless of the proposed 1st ship date.

This particular PCN is related to TI's previous announcement to close our two remaining factories with 150-millimeter production (DFAB in Dallas, Texas, and SFAB in Sherman, Texas). As referenced in the "reason for change" below, these changes are part of our multiyear plan to transition these products to newer, more efficient manufacturing processes and technologies, underscoring our commitment to product longevity and supply continuity.

For questions regarding this notice or to provide acknowledgement of this PCN, you may contact your local Field Sales Representative or the PCN Team (<u>PCN ww admin team@list.ti.com</u>). For sample requests or sample related questions, contact your local Field Sales Representative. As always, we thank you for your continued business.

PCN Team SC Business Services

## 20210315001.1 Attachment: 1

## **Products Affected:**

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

## DEVICE

PCA9534PWR

**CUSTOMER PART NUMBER** 

null

Technical details of this Product Change follow on the next page(s).

PCN Number:	202103	315001.1		PCN D	ate:	Mar 16, 2021
		r Fab site (MIHO8 or FFAB) using qualified Process Technology, Di t update and additional Assembly site/BOM options for select				
Customer Contact:	PC	<u>CN Manager</u>		Dept:		Quality Services
Proposed 1 <sup>st</sup> Ship Date:	Ju	n 16, 2021	Estima Availat		mple	Date provided at sample request.
Change Type:						
Assembly Site		Assembly Process			Asser	mbly Materials
🛛 Design	$\square$	Electrical Specific	ation		Mech	anical Specification
Test Site		Packing/Shipping,	/Labeling		Test	Process
Wafer Bump Site		Wafer Bump Mate	erial		Wafe	r Bump Process
Wafer Fab Site		Wafer Fab Materials			Wafe	r Fab Process
		Part number change				

**PCN Details** 

## **Description of Change:**

Texas Instruments is pleased to announce the qualification of a new fab & process technology (MIHO8 or FFAB, LBC7) and assembly (MLA, Clark-AT, CDAT) site/BOM (MLA, CDAT) options for selected devices as listed below in the product affected section.

	Current Fa	b Site		New Fab	Site
Fab Site	Process	Wafer Diameter	Fab Site	Process	Wafer Diameter
DL-LIN	F0C21	200 mm	MIHO8	LBC7	200 mm
DL-LIN	LIN 50C21 200 mm		FFAB	LBC7	200 mm

The die was also changed as a result of the process change.

The datasheets will be changing as a result of the above mentioned changes. The datasheet change details can be reviewed in the datasheet revision history. The link to the revised datasheet is available in the table below.

Product Folder	Current Datasheet Number	New Datasheet Number	Link to full datasheet
PCA9539	SCPS130G	SCPS130H	http://www.ti.com/product/PCA9539
PCA9554	SCPS128C	SCPS128D	http://www.ti.com/product/PCA9554
PCA9548A	SCPS143F	SCPS143G	http://www.ti.com/product/PCA9548A
PCA9534	SCPS124G	SCPS124H	http://www.ti.com/product/PCA9534
PCA9538	SCPS126F	SCPS126G	http://www.ti.com/product/PCA9538
PCA9535	SCPS129J	SCPS129K	http://www.ti.com/product/PCA9535
PCA9544A	SCPS146F	SCPS146G	http://www.ti.com/product/PCA9544A
PCA9546A	SCPS148G	SCPS148H	http://www.ti.com/product/PCA9546A
PCA9555	SCPS131I	SCPS131J	http://www.ti.com/product/PCA9555
PCA9543A	SCPS169A	SCPS169B	http://www.ti.com/product/PCA9543A
PCA9534A	SCPS141I	SCPS141J	http://www.ti.com/product/PCA9534A
PCA9545A	SCPS147D	SCPS147E	http://www.ti.com/product/PCA9545A
PCA9554A	SCPS127E	SCPS127F	https://www.ti.com/product/PCA9554A

		MLA Cu	rrent	Clark-AT Nev	N
	Mold Compound	d 42086	525	4222198	
	Die Attach Mater	rial 42058	346	4207123	
Group !	5 Device List - FFA	AB/Process migrat	ion & AT/BOM	1 Compare (DB Pa	ackage):
		MLA C	urrent	MLA New	
	Die Attach Mate	erial 4147	'858	4042500	
Packag		AB/Process migrat		CDAT New	
	Mold Compoun	nd 4208	625	4222198	
	Die Attach Mate			4207123	
		MLA Cu	rrent	CDAT New	
	Mold Compoun	MLA Cu		<b>CDAT New</b> 4222198	
-	•	nd 42086	525 346		
Reason These cl factories commitr Anticip	Die Attach Mater tails are provided in for Change: nanges are part of c s to newer, more eff ment to product lone	nd 42086 rial 42058	525 346 on. transition prod processes and ntinuity.	4222198 4207123 ucts from our 150- technologies, unde	erscoring our
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Reason These cl factories commitr Anticipa None Anticipa None Change	Die Attach Mater tails are provided in for Change: hanges are part of co is to newer, more effi- ment to product long ated impact on Fo ated impact on Material beclaration is to product ident te Information:	ad       42086         rial       42058         a the Qual Data Section       42058         bur multiyear plan to       5000000000000000000000000000000000000	ations or Production releations <b>Processes</b> and <b>Processes</b> and <b>Processes</b> and <b>Processes</b> and <b>Processes</b> and <b>Processes</b> and <b>Production</b> releations or Production releations <b>Production</b> releations <b>Production Production Pro</b>	4222198 4207123	erscoring our / negative): are driven from e production orts can be
Reason These cl factories commitr Anticipa None Anticipa None Change	Die Attach Mater tails are provided in for Change: hanges are part of co to newer, more effection ated impact on Fo ated impact on Material beclaration to Impact to he Material beclaration te Information: Chip Site	ad       42086         rial       42058         a the Qual Data Section       42058         bur multiyear plan to       5         ficient manufacturing       9         gevity and supply co       5         brm, Fit, Function, fit       6         aterial Declaration       6         Material Declaration       6         Material Declaration       6         broduction data       7         release. Upon       6         obtained from t       6         Chip Site Origin       Code (20L)	ations or Production releations <b>Processes</b> and <b>Processes</b> and <b>Processes</b> and <b>Processes</b> and <b>Processes</b> and <b>Processes</b> and <b>Production</b> releations or Production releations <b>Production</b> releations <b>Production Production Pro</b>	4222198 4207123	Are driven from are driven from orts can be Chip Site City

Assembly Site	Assembly Site Origin	Assembly Country Code	Assembly City
	(22L)	(23L)	· ·
TI MLA	MLA	MYS	Kuala Lumpur
FMX	MEX	MEX	Aguascalientes
TI CLARK	QAB	PHL	Angeles City, Pampang
TI CDAT	CDA	CHN	Chengdu
TEXAS INSTRUMENTS ADE IN: China DC: 2Q: ISL 1 /260C/UNLIN ISL 1 /260C/UNLIN ISL 1 /260C/UNLIN ISL 1 /260C/UNLIN	C C C C C C C C C C C C C C	(1P) PTAS256 (Q) 3000 (31T) LOT: (4W) SWR (1 (P) (2P) REV: A0 (20L) CSO: DMG	(D) <b>1710</b> 7133710JCP T) 2855550Z9A (V) 0033317
roduct Affected		(ک <u>عل Aso) میں</u> migration):	(23 <u>L) ACO: CHN</u>
CA9543APWR	PCA9544APWRG4	PCA9546APWRE4	PCA9548ARGER
PCA9543APWRG4	PCA9545APWR	PCA9548APWR	
PCA9544APWR	PCA9546APWR	PCA9548APWRG4	
	List (MIHO8/Process	migration + MLA A/T si	te):
PCA9544APWT	PCA9546ADR	PCA9546APWT	PCA9546APWTG4
PCA9545APWT	PCA9546ADT		
Group 3 Device	List (FFAB/Process n	nigration):	
PCA9534APWR	PCA9535PWR	PCA9539PWRG4	PCA9555PWR
PCA9534PWR	PCA9538PWR		PCA9555PWRG4
		PCA9554PWR	PCA9555PWR04
PCA9534PWRG4	PCA9539PWR	PCA9554PWR PCA9554PWRG4	PCA9555PWRG4
PCA9534PWRG4	PCA9539PWR		
Group 4 Device		PCA9554PWRG4	
Group 4 Device	List (FFAB/Process n	PCA9554PWRG4	e & BOM update):
Group 4 Device PCA9535RGER	List (FFAB/Process n PCA9539RGER	PCA9554PWRG4	<b>&amp; BOM update):</b> PCA9555RGERG4
Group 4 Device PCA9535RGER Group 5 Device	List (FFAB/Process n PCA9539RGER	PCA9554PWRG4 nigration + Clark-AT site PCA9555RGER	<b>&amp; BOM update):</b> PCA9555RGERG4
Group 4 Device PCA9535RGER Group 5 Device PCA9555DBR	List (FFAB/Process n PCA9539RGER List (FFAB/Process n	PCA9554PWRG4 nigration + Clark-AT site PCA9555RGER nigration & BOM update)	PCA9555RGERG4
Group 4 Device PCA9535RGER Group 5 Device PCA9555DBR Group 6 Device	List (FFAB/Process n PCA9539RGER List (FFAB/Process n List (FFAB/Process n	PCA9554PWRG4 nigration + Clark-AT site PCA9555RGER nigration & BOM update) nigration + CDAT A/T sit	e & BOM update): PCA9555RGERG4 : e & BOM update):
Group 4 Device PCA9535RGER Group 5 Device PCA9555DBR Group 6 Device	List (FFAB/Process n PCA9539RGER List (FFAB/Process n	PCA9554PWRG4 nigration + Clark-AT site PCA9555RGER nigration & BOM update)	PCA9555RGERG4
Group 4 Device PCA9535RGER Group 5 Device PCA9555DBR Group 6 Device PCA9554ARGTR	List (FFAB/Process n PCA9539RGER List (FFAB/Process n List (FFAB/Process n PCA9534ARGTR	PCA9554PWRG4  nigration + Clark-AT site PCA9555RGER  nigration & BOM update)  nigration + CDAT A/T sit PCA9534RGVR	<b>&amp; BOM update):</b> PCA9555RGERG4 : : : : : : : : : : : : : : : : : : :
PCA9535RGER Group 5 Device PCA9555DBR Group 6 Device PCA9554ARGTR	List (FFAB/Process n PCA9539RGER List (FFAB/Process n List (FFAB/Process n PCA9534ARGTR	PCA9554PWRG4 nigration + Clark-AT site PCA9555RGER nigration & BOM update) nigration + CDAT A/T sit	<b>&amp; BOM update):</b> PCA9555RGERG4 : : : : : : : : : : : : : : : : : : :

## Group 1 (Adding MIHO8 Wafer Fab site) Qual Memo:

#### Qualification Report

#### Approve Date 15-May-2020

#### Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed QBS QBS QBS QBS QBS QBS Product Product Qual Qual Qual Qual Product Product Product Process Reference Test Device: PCA9545AP WR Device: PCA9548AR GER Device: PCA9546AP Device: PCA9543 Device: PCA9544AP Reference Reference Reference Reference Reference Name / Conditior Туре Duration WR TP \$62110 TCA9543AP TCA9544AP TCA9545AP TCA9546AP TCA9548AP WR WR WR WR WR RSA Autoclave 3/231/0 AC 96 Hours \_ 121C ESD CDM 1500 V 1/3/0 1/3/0 1/4/0 1/3/0 1/3/0 ------CDM Per Electrical Datasheet FD Characteri Pass Pass Pass Pass Pass \_ Parameter zation s Early Life Failure FI FR 3/1881/0 48 Hours \_ \_ \_ Rate. 140C Biased HAST, HAST 3/231/0 96 Hours 130C/85% RH ESD -HBM 4000 V 1/3/0 1/3/0 1/3/0 1/3/0 нвм ESD нвм 4500 V 1/3/0 --2 --. \_ --\_ HBM Life Test HTOL 480 Hours 3/231/0 ------\_ \_ --140C High Temp HTSL Storage 420 Hours 3/231/0 . . Bake 170C (Per 1/6/0 1/6/0 1/6/0 1/6/0 1/6/0 LU Latch-up

Туре	Test Name / Condition	Duration	Qual Device: <u>PCA9543</u> <u>APWR</u>	Qual Device: <u>PCA9544AP</u> <u>WR</u>	Qual Device: <u>PCA9545AP</u> <u>WR</u>	Qual Device: <u>PCA9546AP</u> <u>WR</u>	Qual Device: <u>PCA9548AR</u> <u>GER</u>	QBS Product Reference : <u>TCA9543AP</u> <u>WR</u>	QBS Product Reference : <u>TCA9544AP</u> <u>WR</u>	QBS Product Reference : <u>TCA9545AP</u> <u>WR</u>	QBS Product Reference : <u>TCA9546AP</u> <u>WR</u>	QBS Product Reference : <u>TCA9548AP</u> <u>WR</u>	QBS Process Referenc e: <u>TP S62110</u> <u>RSA</u>
		JESD78)											
тс	Temperat ure Cycle, -65/150C	500 Cycles	-	-	-	-	-	-	-	-	-	-	3/231/0
TS	Thermal Shock, - 65/150C	500 Cycles	-	-	-	-	-	-	-	-	-	-	3/231/0

- QBS: Qual By Similarity - Qual Devices PCA9543APWR, PCA9545APWR, PCA9544APWR, and PCA9546APWR are qualified at LEVEL1-260C

- Qual Device PCA9548ARGER is qualified at LEVEL2-260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles Quality and Environmental data is available at TI's external Web site: <u>http://www.ti.com/</u>

Green/Pb-free Status:

## **Qualification Report**

## Approve Date 19-May-2020

#### **Qualification Results**

#### Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: <u>PCA9458APWR</u>	QBS Product Reference: <u>TCA9548APWR</u>	QBS Process Reference: <u>TP S62110RSA</u>	QBS Package Reference: <u>ADS8332IBPW</u>	QBS Package Reference: <u>SN75976A1DGG</u>	QBS Package Reference: <u>TP S51117PW</u>
AC	Autoclave 121C	96 Hours	-	-	3/231/0	1/77/0	3/231/0	3/231/0
CDM	ESD - CDM	1500 V	-	1/3/0	-	-	-	-
ED	Electrical Characterization	Per Datasheet Parameters	-	Pass	-	-	-	-
ELFR	Early Life Failure Rate, 140C	48 Hours	-	-	3/1881/0	-	-	-
HAST	Biased HAST, 130C/85%RH	96 Hours	-	-	3/231/0	-	3/120/0	-
HBM	ESD - HBM	4000 V	-	1/3/0	-	-	-	-
HTOL	Life Test, 140C	480 Hours	-	-	3/231/0	-	-	-
HTOL	Life Test, 155C	240 Hours	-	-	-	-	3/120/0	-
HTSL	High Temp Storage Bake 170C	420 Hours	-	-	3/231/0	-	3/231/0	3/231/0
LU	Latch-up	(Per JESD78)	-	1/6/0	-	-	-	-
тс	Temperature Cycle, -65/150C	500 Cycles	-	-	3/231/0	1/77/0	3/231/0	3/231/0
TS	Thermal Shock, -65/150C	500 Cycles	-	-	3/231/0	-	3/231/0	3/231/0

- QBS: Qual By Similarity

- Qual Device PCA9458APWR is qualified at LEVEL1-260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

## Group 2 (Adding MIHO8 Wafer Fab site + MLA A/T site) Qual Memo:

## **Qualification Report**

## Approve Date 18-May-2020

	Data Displayed as: Number of lots / Total sample size / Total failed											
Туре	Test Name / Condition	Duration	Qual Device: <u>PCA9546ADR</u>	QBS Product Reference: <u>TCA9546APWR</u>	QBS Process Reference: <u>TPS62110RSA</u>	QBS Package Reference: <u>ULQ2003AQDRQ1</u>						
AC	Autoclave 121C	96 Hours	-	-	3/231/0	3/231/0						
CDM	ESD - CDM	1500 V	-	1/3/0	-	-						
ED	Electrical Characterization.	(Per Datasheet Parameters)	-	Pass	-	-						
ELFR	Early Life Failure Rate, 140C	48 Hours	-	-	3/1881/0	-						
HAST	Biased HAST, 130C/85%RH	96 Hours	-	-	3/231/0	3/231/0						
HBM	ESD - HBM	4000 V	-	1/3/0	-	-						
HTOL	Life Test, 125C	1000 Hours	-	-	-	3/231/0						
HTOL	Life Test, 140C	480 Hours	-	-	3/231/0	-						
HTSL	High Temp Storage Bake 150C	1000 Hours	-	-	-	3/135/0						
HTSL	High Temp Storage Bake 170C	420 Hours	-	-	3/231/0	-						
LU	Latch-up	(Per JESD78, Class II)	-	1/6/0	-	-						
тс	Temperature Cycle, - 65/150C	500 Cycles	-	-	3/231/0	3/231/0						
TS	Thermal Shock, - 65/150C	500 Cycles	-	-	3/231/0	-						

#### Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

- QBS: Qual By Similarity

- Qual Device PCA9546ADR is qualified at LEVEL 1-260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

## Group 3 (Adding FFAB Wafer Fab site) Qual Memo:

#### **Qualification Report**

#### Approve Date 15-May-2020

#### Qualification Results

#### Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: <u>PCA953</u> <u>4APWR</u>	Qual Device: <u>PCA953</u> <u>4PWR</u>	Qual Device: <u>PCA9535</u> <u>PWR</u>	Qual Device: <u>PCA9539</u> <u>PWR</u>	Qual Device: <u>PCA955</u> <u>4PWR</u>	Qual Device: <u>PCA955</u> <u>5PWR</u>	QBS Product Reference: <u>TCA9534A</u> <u>PWR</u>	QBS Product Referenc e: <u>TCA9534</u> <u>PWR</u>	QBS Product Referenc e: <u>TCA9535</u> <u>PWR</u>	QBS Product Referenc e: <u>TCA9539</u> <u>PWR</u>	QBS Product Reference: <u>TCA9554A</u> <u>PWR</u>	QBS Product Referenc e: <u>TCA9555</u> <u>PWR</u>	QBS Process Referen ce: <u>TCA641</u> <u>6PW</u>
AC	Autoclave 121C	96 Hours	-	-	-	-	-	-	-	-	-	-	-	-	3/231/0
CDM	ESD - CDM	1000 V	-	-	-	-	-	-	1/3/0	1/3/0	-	-	1/3/0	-	-
CDM	ESD - CDM	1500 V	-	-	-	-	-	-	-	-	1/3/0	1/3/0	-	1/3/0	-
ED	Electrical Characteriz ation.	Per Datasheet Parameters	-	-	-	-	-	-	Pass	Pass	Pass	Pass	Pass	Pass	-
HAST	Biased HAST, 130C/85%R H	96 Hours	-	-	-	-	-	-	-	-	-	-	-	-	3/231/0
HBM	ESD - HBM	2500 V	-	-	-	-	-	-	1/3/0	1/3/0	-	-	1/3/0	-	-
HBM	ESD - HBM	3000 V	-	-	-	-	-	-	-	-	1/3/0	1/3/0	-	1/3/0	-
HTOL	Life Test, 150C	300 Hours	-	-	-	-	-	-	-	-	-	-	-	-	3/231/0
HTSL	High Temp Storage Bake 150C	1000 Hours	-	-	-	-	-	-	-	-	-	-	-	-	3/231/0
LU	Latch-up	(Per JESD78)	-	-	-	-	-	-	1/6/0	1/6/0	1/6/0	1/6/0	1/6/0	1/6/0	-
тс	Temperatur e Cycle, - 65/150C	500 Cycles	-	-	-	-	-	-	-	-	-	-	-	-	3/231/0

- QBS: Qual By Similarity

- Qual Devices PCA9535PWR, PCA9539PWR, PCA9534PWR, PCA9555PWR, PCA9534APWR, PCA9554PWR are qualified at LEVEL1-260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7 eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

## **Qualification Report**

## Approve Date 19-May-2020

#### Qualification Results

#### Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: <u>PCA9538PWR</u>	QBS Product Reference: <u>TCA9538PWR</u>	QBS Process Reference: <u>TCA6416PW</u>
AC	Autoclave 121C	96 Hours	-	-	3/231/0
CDM	ESD - CDM	1500 V	-	1/3/0	-
ED	Electrical Characterization.	(Per Datasheet Parameters)	-	Pass	-
HAST	Biased HAST, 130C/85%RH	96 Hours	-	-	3/231/0
HBM	ESD - HBM	4000 V	-	1/3/0	-
HTOL	Life Test, 150C	300 Hours	-	-	3/231/0
HTSL	High Temp Storage Bake 150C	1000 Hours	-	-	3/231/0
LU	Latch-up	(Per JESD78)	-	1/6/0	-
TC	Temperature Cycle, -65/150C	500 Cycles	-	-	3/231/0

- QBS: Qual By Similarity - Qual Device PCA9538PWR is qualified at LEVEL1-260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7 eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free (SMT) and Green

## Group 4 (Adding FFAB Wafer Fab site + Clark-AT + BOM change) Qual Memo:

#### **Qualification Report**

#### Approve Date 18-May-2020

#### Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

	Data Displayed as: Number of lots / Total sample size / Total failed											
Туре	Test Name / Condition	Duration	Qual Device: <u>.PCA9539</u> <u>RGER</u>	Qual Device: <u>PCA9535RG</u> <u>ER</u>	Qual Device: <u>PCA9555RG</u> <u>ER</u>	QBS Product Reference: <u>TCA9535PW</u> <u>R</u>	QBS Product Reference: <u>TCA9539PW</u> <u>R</u>	QBS Product Reference: <u>TCA9555PW</u> <u>R</u>	QBS Process Reference : <u>TCA6416P</u> <u>W</u>	QBS Package Reference : <u>BQ9000RS</u> <u>M</u>	QBS Package Reference: <u>TPS63000DRC</u> <u>R</u>	QBS Package Referenc e: <u>TPS7A4701</u> <u>QRGWRQ1</u>
AC	Autoclave 121C	96 Hours	-	-	-	-	-	-	3/231/0	3/231/0	3/231/0	3/231/0
CDM	ESD - CDM	1500 V	-	-	-	1/3/0	1/3/0	1/3/0	-	-	-	-
ED	Electrical Characterizati on	Per Datasheet Parameters	-	-	-	Pass	Pass	Pass	-	-	-	-
HAST	Biased HAST 130C/85%RH	96 Hours	-	-	-	-	-	-	3/231/0	3/112/0	-	3/231/0
HBM	ESD - HBM	3000 V	-	-	-	1/3/0	1/3/0	1/3/0	-	-	-	-
HTOL	Life Test, 125C	1000 Hours	-	-	-	-	-	-	-	-	-	3/231/0
HTOL	Life Test, 140C	480 Hours	-	-	-	-	-	-	-	3/231/0	-	-
HTOL	Life Test, 150C	300 Hours	-	-	-	-	-	-	3/231/0	-	-	-
HTSL	High Temp Storage Bake 150C	1000 Hours	-	-	-	-	-	-	3/231/0	-	-	1/45/0
HTSL	High Temp. Storage Bake 170C	420 Hours	-	-	-	-	-	-	-	3/231/0	-	-
LU	Latch-up	Per JESD78	-	-	-	1/6/0	1/6/0	1/6/0	-	-	-	-
TC	Temperature Cycle - 65/150C	500 Cycles	-	-	-	-	-	-	3/231/0	3/231/0	3/231/0	3/231/0
WBP	Bond Pull	Wires	-	-	-	-	-	-	-	-	3/228/0	-
WBS	Ball Bond Shear	Wires	-	-	-	-	-	-	-	-	3/228/0	-

- QBS: Qual By Similarity

- Qual Devices PCA9535RGER, PCA9555RGER, and PCA9539RGER are qualified at LEVEL2-260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours - The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

The following are equivalent 15C options based on an activation energy of 0.7eV. 150C/1CHouls, and 170C/420 Ho
 The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free (SMT) and Green

## Group 5 (Adding FFAB Wafer Fab site + BOM change) Qual Memo:

### **Qualification Report**

#### Approve Date 18-May-2020

Data Displayed as: Number of lots / Total sample size / Total failed											
Туре	Test Name / Condition	Duration	Qual Device: <u>PCA9555</u> <u>DBR</u>	QBS Product Reference: <u>TCA9555PW</u> <u>R</u>	QBS Process Referenc e: <u>TCA6416P</u> <u>W</u>	QBS Package Reference: <u>CLVC4245AD</u> <u>BR</u>	QBS Package Referenc e: <u>MAX232D</u> <u>R</u>	QBS Package Reference: <u>TL1454ACDB</u> <u>R</u>	QBS Package Reference: <u>TLC320AD77CD</u> <u>BR</u>		
AC	Autoclave 121C	96 Hours	-	-	3/231/0	-	-	3/231/0	3/231/0		
CDM	ESD - CDM	1500 V	-	1/3/0	-	-	-	-	-		
ED	Electrical Characteriza tion	Per Datasheet Parameters	-	Pass	-	-	-	-	-		
HAST	Biased HAST, 130C/85%R H	96 Hours	-	-	3/231/0	-	3/231/0	-	-		
HBM	ESD - HBM	3000 V	-	1/3/0	-	-	-	-	-		
HTOL	Life Test, 150C	300 Hours	-	-	3/231/0	-	3/231/0	-	-		
HTSL	High Temp Storage Bake 150C	1000 Hours	-	-	3/231/0	-	-	-	-		
HTSL	High Temp. Storage Bake, 170C	420 Hours	-	-	-	-	-	3/227/0	3/231/0		
LU	Latch-up	(Per JESD78)	-	1/6/0	-	-	-	-	-		
тс	Temperature Cycle, - 65/150C	500 Cycles	-	-	3/231/0	1/77/0	-	3/231/0	3/231/0		

## Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

- QBS: Qual By Similarity

- Qual Device PCA9555DBR is qualified at LEVEL1-260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7 eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

## Group 6 (Adding FFAB + CDAT A/T site & BOM change) Qual Memo:

## Qualification Report

## Approve Date 01-Mar-2021

					1003/1000				
Туре	Test Name / Condition	Duration	Qual Device: <u>.PCA9534R</u> <u>GV</u>	Qual Device: <u>PCA9534AR</u> <u>GT</u>	Qual Device: <u>PCA9554AR</u> <u>GT</u>	QBS Process Referenc e: <u>TCA6416P</u> <u>W</u>	QBS Package Reference: <u>BQ24196RG</u> <u>ER</u>	QBS Package Reference: <u>TP S2546QRTER</u> <u>Q1</u>	QBS Package Reference: <u>TP \$3850G09D</u> <u>RC</u>
AC	Autoclave 121C	96 Hours	-	-	-	3/231/0	3/231/0	3/231/0	3/231/0
CDM	ESD - CDM	1500 V	1/3/0	1/3/0	1/3/0	-	-	-	-
ED	Electrical Characteri zation	Per Datasheet Paramete rs	Pass	Pass	Pass	-	-	-	-
HAST	Biased HAST, 130C/85% RH	96 Hours	-	-	-	3/231/0	-	3/231/0	3/231/0
HBM	ESD - HBM	4000 V	1/3/0	1/3/0	1/3/0	-	-	-	-
HTOL	Life Test, 150C	300 Hours	-	-	-	3/231/0	-	3/231/0	1/77/0
HTSL	High Temp Storage Bake 150C	1000 Hours	-	-	-	3/231/0	-	3/148/0	-
HTSL	High Temp Storage Bake 170C	420 Hours	-	-	-	-	-	-	3/231/0
LU	Latch-up	(Per JESD78)	1/6/0	1/6/0	1/6/0	-	-	-	-
тс	Temperatu re Cycle, - 65/150C	500 Cycles	-	-	-	3/231/0	3/231/0	3/231/0	3/231/0
WBP	Bond Pull	Wires	1/76/0	1/76/0	1/76/0	-	-	-	-
WBS	Ball Bond Shear	Wires	1/76/0	1/76/0	1/76/0	-	-	-	-

## Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

- QBS: Qual By Similarity

- Qual Devices PCA9534ARGT, PCA9554ARGT, and PCA9534RGV are qualified at LEVEL2-260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable - The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

### Green/Pb-free Status:

## Group 7 (Adding MIHO8 + CDAT A/T site & BOM update) Qual Memo:

#### Qualification Report

#### Approve Date 04-Mar-2021

Qualification Results					
Data Displayed as: Number of lots / Total sample size /	Total failed				

Туре	Test Name / Condition	Duration	Qual Device: <u>PCA9544ARGY</u>	Qual Device: <u>PCA9545ARGY</u>	Qual Device: <u>PCA9546ARGV</u>	QBS Process Reference: <u>TPS62110RSA</u>	QBS Package Reference: <u>BQ24196RGER</u>	QBS Package Reference: <u>TPS3850G09DRC</u>	QBS Package Reference: <u>TS3A5017QRGYQ1</u>
AC	Autoclave 121C	96 Hours	-	-	-	3/231/0	3/231/0	3/231/0	3/231/0
CDM	ESD - CDM	1500 V	1/3/0	1/3/0	1/3/0	-	-	-	-
ED	Electrical Characterization	Per Datasheet Parameters	Pass	Pass	Pass	-	-	-	-
ELFR	Early Life Failure Rate, 140C	48 Hours	-	-	-	3/1881/0	-	-	-
HAST	Biased HAST, 130C/85%RH	96 Hours	-	-	-	3/231/0	-	3/231/0	3/231/0
HBM	ESD - HBM	4000 V	1/3/0	1/3/0	1/3/0	-	-	-	-
HTOL	Life Test, 125C	1000 Hours	-	-	-	-	-	-	3/231/0
HTOL	Life Test, 140C	480 Hours	-	-	-	3/231/0	-	-	-
HTOL	Life Test, 150C	300 Hours	-	-	-	-	-	1/77/0	-
HTSL	High Temp Storage Bake 150C	1000 Hours	-	-	-	-	-	-	3/135/0
HTSL	High Temp Storage Bake 170C	420 Hours	-	-	-	3/231/0	-	3/231/0	-
LU	Latch-up	(Per JESD78)	1/6/0	1/6/0	1/6/0	-	-	-	-
тс	Temperature Cycle, -65/150C	500 Cycles	-	-	-	3/231/0	3/231/0	3/231/0	3/231/0
TS	Thermal Shock, - 65/150C	500 Cycles	-	-	-	3/231/0	-	-	-
WBP	Bond Pull	Wires	1/76/0	1/76/0	1/76/0	-	3/228/0	-	3/90/0
WBS	Ball Bond Shear	Wires	1/76/0	1/76/0	1/76/0	-	3/228/0	-	3/90/0

- QBS: Qual By Similarity

- Qual Devices PCA9545ARGY, PCA9546ARGV, and Device PCA9544ARGY are qualified at LEVEL2-260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

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#### Green/Pb-free Status:

Qualified Pb-Free (SMT) and Green

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